

Notice of References Cited	Application/Control No. 09/994,283	Applicant(s)/Patent Under Reexamination CHUN ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,323,921	11-2001	Kurauchi et al.	349/106
	B	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 10-268356	10-1998	Japan	Takebayashi et al	
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NON-PATENT DOCUMENTS

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